



THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Jack O. Chu et al.

Date: May 8, 2002

Serial No.: 09/692,606

Group Art Unit: 1765

Filed: October 19, 2000

Examiner:

For: LAYER TRANSFER OF LOW DEFECT
SiGe USING AN ETCH-BACK PROCESS

Docket No.: YOR920000344US1

Assistant Commissioner for Patents
Washington, D.C. 20231

INFORMATION DISCLOSURE STATEMENT UNDER CFR 1.56 AND 1.97(c)(1)

Sir:

In compliance with the duty of disclosure under 37 CFR 1.56, enclosed is an International Search Report dated 18 March 2002, a copy of the references cited therein, except US 5,906,951, and completed form PTO 1449 listing the references. The International Search Report was issued in application PCT/GB01/04159 filed 17 September 2001 and is a counterpart international application with respect to this application from which priority is claimed.

US 5,906,951 cited in the search report is already of record.

Each item of information contained in the information disclosure statement herein was cited in a communication from a receiving (foreign) patent office in a counterpart international (foreign) application not more than three months prior to the filing of the information disclosure statement herein.

Please charge an fee necessary to enter this paper to deposit account 09-0468.

Respectfully submitted,
Attorney for the Applicants

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